

10/23/2014



**RELIABILITY MONITOR REPORT
FOR**

San Antonio 0.8 μ m Silicon Gate with EEPROM (EB8)

MAXIM INTEGRATED

**160 RIO ROBLES
SAN JOSE, CA 95134**

**This Report was prepared by
MAXIM INTEGRATED Reliability Engineering**

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX1781ETM+

The calculated failure rate for devices using this process is:

FAILURE RATE: MTTF (YRS): 30618 QUANTITY: 238 FAILS: 0 FITS: 3.7

The parameters used to calculate this failure rate are as follows:

Cf: 60% Ea: 0.7 Tu: 25 °C

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 10/1/2013 and 9/30/2014 .

Process Information:

Process Description: San Antonio 0.8µm Silicon Gate with EEPROM (EB8)

OPERATING LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	1326	MAX1781ETM+	135°C	1000 HRS	79	0	TML5AA0Z8QA
HIGH TEMP OP LIFE	1326	MAX1781ETM+	135°C	1000 HRS	79	0	TML5AA0Z8QB
HIGH TEMP OP LIFE	1326	MAX1781ETM+	135°C	1000 HRS	80	0	TML5AA0Z8QC
Total:						0	

STORAGE LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
STORAGE LIFE	1326	MAX1781ETM+	150°C	1000 HRS	79	0	TML5AA0Z8QA
STORAGE LIFE	1326	MAX1781ETM+	150°C	1000 HRS	80	0	TML5AA0Z8QB
STORAGE LIFE	1326	MAX1781ETM+	150°C	1000 HRS	80	0	TML5AA0Z8QC
Total:						0	

TEMPERATURE CYCLE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
TEMP CYCLE, 5' RAMP, 10' DWELL	1326	MAX1781ETM+	-65C TO +150C (Condition C)	1000 CYS	77	1	TML5AA0Z8QA
TEMP CYCLE, 5' RAMP, 10' DWELL	1326	MAX1781ETM+	-65C TO +150C (Condition C)	1000 CYS	76	0	TML5AA0Z8QB
Total:						1	

FAILURE RATE: MTTF (YRS): 30618 QUANTITY: 238 FAILS: 0 FITS: 3.7